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Section B

Beam Interactions with Materials and Atoms

Editors: H. H. Andersen & S. T. Picraux

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Lasers for Ultrashort Light Pulses

by **Joachim Herrmann** *and* **Bernd Wilhelmi**

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The rapid development of picosecond lasers and picosecond light pulse diagnostics has led to enormous progress in the entire field of ultrafast measuring techniques during the last 15 years. Ultashort light pulses permit novel investigations of extremely rapid physical, chemical and biological phenomena on the picosecond and even femtosecond time scale. The high time resolution attained using picosecond lasers allows new and deeper insights into the nature and especially into the temporal evolution of some extremely fundamental processes in materials, most of which occur on a picosecond time scale. Among the fundamental processes that have been measured are the free decay of molecular vibrations and of orientational fluctuations in liquids, relaxation processes in small and large molecules, phonon decay, exciton decay and energy migration in solids. Moreover picosecond technology has provided new capabilities both for the manipulation of photophysical and photochemical processes and for making extremely fast electro-optical components such as switches, modulators and receivers.

The present rapid expansion of research work on picosecond lasers and their application makes it difficult to survey and comprehend the large number of publications in this field. This book aims to provide a thorough introduction to the field starting with the very basic and moving on to an advanced level.
The authors have provided a guide for physicists, chemists, biologists and engineers as well as for students in these fields who wish to become familiar with the generation and measurement of ultrashort light pulses and their application.

Contents: Preface. Introduction. Notations and Symbols. 1. Fundamentals of the interaction between light pulses and matter. 2. Fundamentals of lasers for ultrashort light pulses. 3. Methods of measurement. 4. Active modelocking. 5. Synchronously pumped lasers. 6. Passive modelocking of dye lasers. 7. Passive modelocking of solid state lasers. 8. Nonstationary nonlinear optical processes. 9. Ultrafast spectroscopy. References. Subject index.

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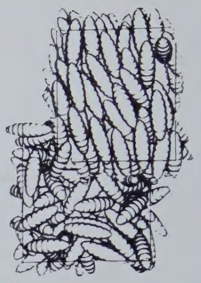

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